

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10750175	DANG ET AL.
	Examiner	Art Unit
	Trimmings, John P	2117

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
326/41,38, 714/724,726,734,731,30. Text strategy attaced (see EAST printout).	4/9/2007	jpt
Dble Patent Search: Negative (see printout).	4/9/2007	jpt
NPL Search: scan chains and fpga or pld and test mode.	4/9/2007	jpt
326/41,38,40, 714/724,727,725,729,742,726,734,731,30. Text strategy attached (see EAST printout).	1/14/2008	jpt
Dble Patent Search: Negative (see printout).	1/17/2008	jpt
NPL Search: Negative.	1/17/2008	jpt

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner